<u>询"74ACT11151"供应商</u>

- Inputs Are TTL-Voltage Compatible
- 8-Line to 1-Line Multiplexers Can Perform as: Boolean Function Generators, Parallel-to-Serial Converters, Data Source Selectors
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- *EPIC* [™] (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

description

This monolithic data selector/multiplexer provides full binary decoding to select one-of-eight data sources. The strobe input (\overline{G}) must be at a low logic level to enable the inputs. A high level at the strobe terminal forces the W output high and the Y output low.

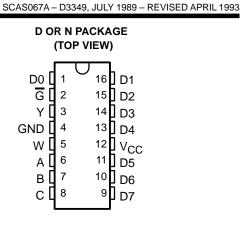
The 74ACT11151 is characterized for operation from – 40° C to 85° C.

INPUTS				OUTPUTS		
S	BELEC	Т	STROBE		w	
С	В	Α	G	T	vv	
Х	Х	Х	Н	L	Н	
L	L	L	L	D0	D0	
L	L	Н	L	D1	D1	
L	Н	L	L	D2	D2	
L	н	Н	L	D3	D3	
н	L	L	L	D4	D4	
н	L	Н	L	D5	D5	
Н	Н	L	L	D6	D6	
Н	н	Н	L	D7	D7	

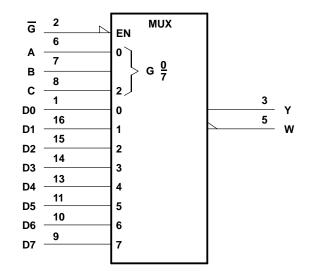
FUNCTION TABLE

H = high level, L = low level, X = irrelevant

D0, D1, . . . D7 = the level of the respective D input



logic symbol[†]

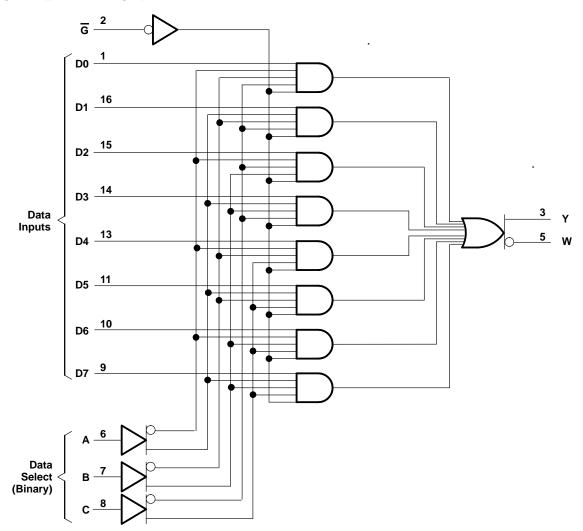


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, VI (see Note 1)	$\dots -0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)	$\dots -0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, I_{OK} (V _O < 0 or V _O > V _{CC})	± 50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	± 50 mA
Continuous current through V _{CC} or GND	
Storage temperature range	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

		MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
VO	Output voltage	0	VCC	V
ЮН	High-level output current		-24	mA
IOL	Low-level output current		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
TA	Operating free-air temperature	- 40	85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	T _A = 25°C			MIN	MAX	UNIT
FARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX		WAA	UNIT
		4.5 V	4.4			4.4		
	I _{OH} = - 50 μA		5.4			5.4		
∨он	1 04 mA	4.5 V	3.94			3.8		V
	I _{OH} = – 24 mA		4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	101 - 50 114	4.5 V			0.1		0.1	V
	l _{OL} = 50 μA	5.5 V			0.1		0.1	
VOL	le: - 24 mA	4.5 V			0.36		0.44	
	I _{OL} = 24 mA	5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
Ц	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		±1	μA
Icc	$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V			8		80	μA
ΔI _{CC} ‡	One input at 3.4 V, Other inputs at GND or V	′CC 5.5 V			0.9		1	mA
Ci	$V_I = V_{CC}$ or GND	5 V		3.5				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V to V_{CC}.



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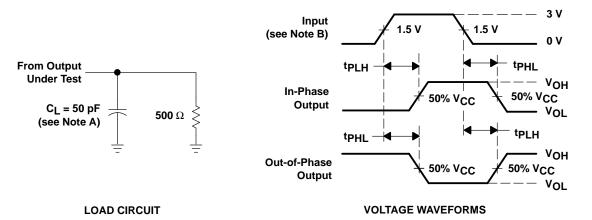
switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T _A = 25°C			MIN	МАХ	UNIT
FARAMETER			MIN	TYP	MAX	WIIN	MAX	UNIT
^t PLH		Y	3.6	6.8	9.9	3.6	11	ns
^t PHL	A, B, or C		3.1	6.7	9.5	3.1	10.5	
^t PLH	A, B, or C	w	2.9	6.3	9	2.9	10	ns
^t PHL			2.7	6.3	9.3	2.7	10.4	
^t PLH	Any D	Y	3.2	5.7	7.5	3.2	8.3	ns
^t PHL			2.2	5.2	8	2.2	8.8	
^t PLH	Any D	W	2.1	4.7	7.3	2.1	7.8	ns
^t PHL			2.7	5.1	6.9	2.7	7.6	115
^t PLH	G	Y	1.5	3.7	5.8	1.5	6.3	ns
^t PHL			2.1	4.0	5.6	2.1	6.2	
^t PLH	G	w	2.5	4.4	6.1	2.5	6.7	
^t PHL			1.7	4.1	6.4	1.7	6.9	ns

operating characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	56	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. CL includes probe and jig capacitance.

B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f = 3 ns, t_f = 3 ns. C. The outputs are measured one at a time with one input transition per measurement.

The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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